VESP Technology Corp.

Report No.：VWO5-23030057-CDM
Report Ver.：01
Report Date：2023/03/16

VESP Technology Corporation

Address: Area A, 1st Floor, Building 5, Mingzhu Industrial Park, High-tech Zone, Hefei, Anhui

TEL: +86-21-3880-9688 FAX: +86-21-5080-4105

CDM Test Report

Testing laboratory is accredited by

IEC quality assessment system (IECQ)：ISO/IECQ 17025 (Certificate No.：IECQ-L ULTW 21.0001)

	Signature	Date
Testing Engineer	Rizer Yao	2023/03/16
Technical Manager	Alina Zhang	2023/03/16
Approval Manager	Jones Fan	2023/03/16

NOTE：

- This report is generated subject to certain conditions (including but not limited to: designated samples, designated environment parameters and designated input signals). VESP Technology Co., Ltd. does not guarantee that the test results under different conditions or generated by other people will coincide with this report.
- This report shall be effective only if the authorized staff of VESP Technology Co., Ltd. signs on it. VESP Technology Co., Ltd. is not responsible for any copy or partial content of this report.
- VESP Technology Co., Ltd. is not responsible for whether the samples tested in this report will function well as their original design and/or meet any expectation.

VESP Technology Corp.

Report No. : VWO5-23030057-CDM
Report Ver. : 01
Report Date : 2023/03/16

1. Application Information：

1.1 Test Items：Charge Device Model (CDM)

1.2 Test Serial No.：VWO5-23030057

2. Customer Basic Information：

2.1 Company：Chipintelli Technology Co., Ltd.

2.2 Applicant：Jiao He

2.3 Address：The 12th floor,Building 4A, Jingronghui, No.200 Tianfu 5th Street, High-tech Zone, Chengdu, China.

2.4 Package/Pin Count：TSSOP/24

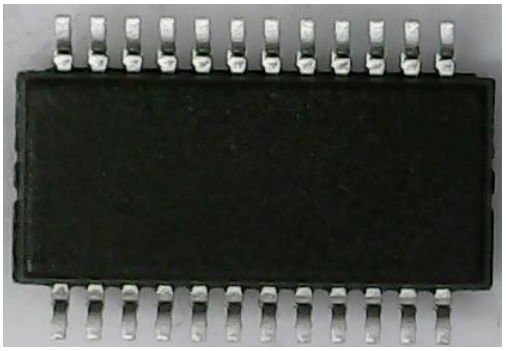
2.5 Application Date：2023/03/10

2.6 Tested Date：2023/03/10

2.7 Device Information：

Device Name	Lot No.	Sample Q’ ty (ea)
CI1302	BJ2221	3

2.8 Device Photos：

Top View	Bottom View
	

3. Environmental Conditions of Laboratory：

3.1 Temperature：22.7°C

3.2 Humidity：51.6% R.H.

4. Test Equipment：

4.1 Test Item：Charge Device Mode

4.2 Test Equipment：

Item	Test Equipment	Serial No.	Calibration Expiration
CDM	Thermo Fisher Scientific Orion2	1506254	2023/09/05

5. Test Procedure：

5.1 Reference Specification：ANSI/ESDA/JEDEC JS-002-2018

5.2 Test Procedure and Conditions：

5.2.1 Test Voltage：±500V~±2000V,Step: 500V

5.2.2 Pin Assignment：

VIN5V 5.5V: 2
AVDD 3.6V: 1
VDD33 3.6V: 3
VDD11 1.2V: 4
AGND: 24
GND: 5,8
IP 3.6V: 6,18,19,20,21
OP 3.6V: 7,17,22,23

IO 3.6V: 9,10,11,12,13,14,15,16

6. Test Result：

Model：CDM	ESD Sensitivity Pass: ±2000V		V Class： C3 Note： Bases on ANSI/ESDA/JEDEC JS-002-2018 CLASS C0a :<125 V CLASS C0b :125 to <250 V CLASS C1 :250 to <500 V CLASS C2a :500 to <750 V CLASS C2b :750 to <1000 V CLASS C3 :≥ 1000 V
Pin Combination	Sample Size	Pass Voltage	
ALL PINS	3	2000V	

7. Special Remarks：NA

8. Attachment：

Charge Device Model： ±2000V Modes

(Unit：Volt)

Test Mode	CDM ±2000V Mode		
Pass Voltage / Pin Name	#C1	#C2	#C3
1	PASS	PASS	PASS
2	PASS	PASS	PASS
3	PASS	PASS	PASS

4	PASS	PASS	PASS
5	PASS	PASS	PASS
6	PASS	PASS	PASS
7	PASS	PASS	PASS
8	PASS	PASS	PASS
9	PASS	PASS	PASS
10	PASS	PASS	PASS
11	PASS	PASS	PASS
12	PASS	PASS	PASS
13	PASS	PASS	PASS
14	PASS	PASS	PASS
15	PASS	PASS	PASS
16	PASS	PASS	PASS
17	PASS	PASS	PASS
18	PASS	PASS	PASS
19	PASS	PASS	PASS
20	PASS	PASS	PASS
21	PASS	PASS	PASS
22	PASS	PASS	PASS
23	PASS	PASS	PASS
24	PASS	PASS	PASS

The tested Sample (units) was complied with test level ±2000V, I-V curve shift ≤ 30%.

Blank Below